

			02.11.2	
RefMat No	38		Category 1 Critical Dimensions	
	COMAR		Category 2 Lateral (X-Y-axis, 1-dim)	
	and the second s		Category 3 Single Step	
			Category 4	
T			Category 5	
			,,	
combina	ation of step height and pitch			
	Included in Coldmasse: Green 1 -> YES Blue 0 -> NO Included in Category 3   ype of RefMat: RM   ame of RM: NanoLattice (TM) (NLSM) 100 nm pich standard scripton   Surface: Topography Standards: (STS), gratings with near perfect periodicity combination of step height and pich.   Link http://www.vlsistandards.com/products/dimensional/ststandards.asp?sid=47   Link http://www.vlsistandards.com/products/dimensional/ststandards.asp?sid=47   Catiloration of AFM   Gatiloration of Step height   MeanValue 18   MeanValue 180   Catiloration of AFM   Catiloration of Step height   MeanValue 180   MeanValue 180   Catiloration of AFM   Catiloration of SteM   Catiloration of SteM   Catiloration of SteM   Catiloration of MeanValue   Devicer No 3   Web address http://www.vlsistandards.com   rowder VLSI Standards, Inc.   Order Curritry San Jace   State Person Marc Helvey, ed. 108 Country			
	lateral distance			
)		MeanValue	<b>nm</b> Uncertainty	
Calibration of	AEM		Characterized by	
	-			
	VVLIW			
Calibration of				
	Web address http			
Provider No		://www.visistanda	ards.com	
Provider	VLSI Standards, Inc.			
Contact Person	Marc Helvey, ext. 108	Country	USA	
Email	sales.support@vlsistd.com	City	San Jose	
Phone	(408) 428-1800	City Code	CA 95134-2006	
	r	Street + No	3087 North First Street	